

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	707/1,2,3,10,100,101,102	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:49
L2	15596	(707/1,2,3,10,100,101,102).CCLS.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:49
L3	2	2 and star adj map\$4	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:51
L4	59	star adj map\$4	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:51
L5	160	star near3 map\$4	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:52
L6	128	5 and @ad<"20011231"	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:04
L7	43	6 and (database)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:53
L8	7	7 and (bit adj map\$6)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:56
L9	4	8 and (outer adj join or outerjoin)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:59
L10	15713	bit adj map\$6	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:57
L11	19575	bit adj (map\$6 or index\$5 or array\$2)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:58
L12	541	2 and 11	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:58
L13	23599	"707"/\$.ccls.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:58
L14	462	12 and @ad<"20011231"	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:04
L15	234	(outer adj join or outerjoin)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:59

L16	80	(outer adj join\$% or outerjoin\$6)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:00
L17	1471	(outer adj join\$4 or outerjoin\$6)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:00
L18	8	17 and 14	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:04
L19	821	2 and (bit near3 (map\$6 or array\$3 or index\$7))	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:04
L20	687	19 and @ad<"20011231"	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:16
L21	687	20 and @ad<"20011231"	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:17
L22	21	21 and (outer near3 join\$5 or outerjoin\$4)	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:08
L23	4035	ncr.as.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:08
L24	9	bhashyam.in.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:08
L25	4	23 and 24	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:08
L26	2	25 and star	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:10
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L28	49	(("10038849") or ("The Patent Linguistics Utility System(PLUS) is a USPTO automated search") or ("systemforU.S. Patentsfrom1971tothepresent. PLUSisa") or ("query-by-example search system which produces a list of patents that are") or ("most closely related linguistically to the application searched. This") or ("search was prepared by the staff of the ScientificandTechnical") or ("InformationCenter,SIRA.") or ("5848408") or ("6618729") or ("6105020") or ("6564212") or ("6633883") or ("5899988") or ("6725223") or ("6446063") or ("6711563") or ("6014733") or ("5802521") or ("6279007") or ("5444842") or ("5903888") or ("6144957") or ("6360213") or ("6442539") or ("6487549") or ("6502089") or ("6507835") or ("6564204") or ("6745173") or ("6163774") or ("6374235") or ("5761652") or ("5864842") or ("5903893") or ("5724577") or ("5758145") or ("6226639") or ("6226639") or ("6122644") or ("6253197") or ("6263331") or ("5903887") or ("5873074") or ("5978793") or ("5819256") or ("6226634") or ("6226634") or ("5883722") or ("5884307") or ("6285994") or ("5812651") or ("6182089") or ("5365251") or ("5465322") or ("5608909") or ("5619675") or ("5781722")).PN. or (PLUSSearchResultsforS/N10038849 ,SearchedNovember30,2004).CCLS.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:15
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L30	7	"outer joins".ti.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:17
L31	7	30 and @ad<"20011231"	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:16
L32	11	"outer joins".clm.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:17

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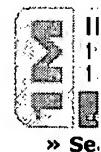
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outer join

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Bhargava, G.; Goel, P.; Iyer, B.;

Data Engineering, 1996. Proceedings of the Twelfth International Conference on , 26 Feb.-1 March 1996

Pages:441 - 449

[\[Abstract\]](#) [\[PDF Full-Text \(676 KB\)\]](#) IEEE CNF**2 Outer joins and filters for instantiating objects from relational data through views**

Byung Suk Lee; Wiederhold, G.;

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[\[Abstract\]](#) [\[PDF Full-Text \(1056 KB\)\]](#) IEEE JNL**3 DB2 for OS/390 V5 vs. V6 outer join performance**

Weihrauch, M.;

Performance Analysis of Systems and Software, 2000. ISPASS. 2000 IEEE International Symposium on , 24-25 April 2000

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Systems, Man and Cybernetics, 1992., IEEE International Conference on , 18-Oct. 1992

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**5 Logic-based approach for realizing a federated information system**

*Whang, W.K.; Navathe, S.B.; Chakravarthy, S.;*

Interoperability in Multidatabase Systems, 1991. IMS '91. Proceedings., First International Workshop on , 7-9 April 1991

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